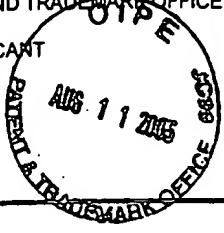


Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. MI22-1748	SERIAL NO. 09/879,231
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT: Garo J. Derderian et al.	
				FILING DATE June 11, 2001	GROUP 2818



U.S. PATENT DOCUMENTS								
*Examiner's Initials	AA	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
TL	AA	6,359,295 B2	03/2002	Lee et al.	—	—	/	
TL	AB	6,596,602 B2	07/2003	Lizuka et al.	—	—		
TL	AC	6,627,462 B1	09/2003	Yang et al.	—	—		
TL	AD	6,664,186 B1	12/2003	Callegari et al.	—	—		
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FOREIGN PATENT DOCUMENTS								
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TL	AJ	KR 2002002157 A	05/2003	Lee, J.W.	—	—	/	
TL	AK	EP 1 508 906 A2	02/2005	Lee et al.	—	—		
	AL				—	—		
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)								
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EXAMINER		DATE CONSIDERED <i>Chad</i> 9/8/05						
<p>*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.</p>								

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Form PTO-1459		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. M22-1748		SERIAL NO. 09/879,231		
<div style="text-align: center;"> LIST OF ART CITED BY APPLICANT (Use several sheets if necessary) </div>				APPLICANT <u>Caro J. Dorderian</u>				
				PRIORITY FILING DATE June 11, 2001		GROUP 7818		
U.S. PATENT DOCUMENTS								
*Examiner Initials		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
<u>TL</u>	AA	6,322,722	04/99	Pelizzoni et al				
	AB	6,304,070	3/01	Kim				
	AC	6,207,487	3/01	Kim et al				
	AD	6,391,803	3/02	Kim et al				
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<u>TL</u>	AM	KR 2002002157A	01/2002	Korea				
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OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)								
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EXAMINER <u>Thane</u>				DATE CONSIDERED <u>10/14/03</u>				
<small>*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.</small>								

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Form PTO 446 U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. M22-1748		SERIAL NO. 09/879,231	
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT Garo J. Derderian	
PRIORITY FILING DATE June 11, 2001				GROUP 2818	

U.S. PATENT DOCUMENTS							
*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
R	AA	09/653,156	Agarwal (as amended 3/5/2002)			08/2000	
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FOREIGN PATENT DOCUMENTS							
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*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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Form PTO-1349

U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICEATTY. DOCKET NO.
M122-1748SERIAL NO.
09/879,231LIST OF ART CITED BY APPLICANT
(Use several sheets if necessary)

APPLICANT Garo J. Derderian

PRIORITY FILING DATE
June 11, 2001GROUP
2818

U.S. PATENT DOCUMENTS

Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
AA	09/652,532		Derderian (as amended 11/29/2001)			08/31/2000
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FOREIGN PATENT DOCUMENTS

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*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Form PTO-1449

U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICEATTY. DOCKET NO.
M122-1745SERIAL NO.
09/879,231

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LIST OF ART CITED BY APPLICANT
(Use several sheets if necessary)

APPLICANT Garo J. Derderian

PRIORITY FILING DATE
June 11, 2001GROUP
2818

U.S. PATENT DOCUMENTS

*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
TL	AA	2002/0064915A1	05/2002	Kitamura			
TL	AB	2001/0023110A1	09/2001	Fukuzumi et al			
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FOREIGN PATENT DOCUMENTS

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OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

TL	AP		A.W. Ott, et al., "Atomic layer controlled deposition of Al ₂ O ₃ films using binary reaction sequence chemistry" Applied Surface Science (107) 1996, pps. 128-136.
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*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. M123-1748		SERIAL NO. 09/879231	
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT Caro J. Dardarion			
				PRIORITY FILING DATE June 11, 2001		GROUP 2815	
U.S. PATENT DOCUMENTS							
Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
TL	AA	2002/0064915A1	05/2002	Examiner			
TL	AB	2001/0023110A1	09/2001	Poluninski et al			
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FOREIGN PATENT DOCUMENTS							
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OTHER REFERENCES (Including Author, Title, Date, Patent Page, Etc.)							
TL	AP		A.W. Oz, et al, "Atomic layer controlled deposition of Al ₂ O ₃ films using binary reaction sequence chemistry" Applied Surface Science (107) 1994, pp. 128-136.				
	AQ						
	AR						
EXAMINER <i>TL</i>				DATE CONSIDERED <i>2/04/03</i>			
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with 35 USC 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							

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		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. M122-1748		SERIAL NO. 02879,231		
		LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)						
		APPLICANT: Garo J. Dardarian				PRIORITY FILING DATE June 11, 2003		GROUP 2818
U.S. PATENT DOCUMENTS								
Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date if Appropriate	
TL ↓	AA	5,126,283	06/1992	Fimchowit et al	—	—	—	
	AB	5,625,233	04/1997	Cabral, Jr. et al	—	—	—	
	AC	6,353,519	03/2002	Lee	—	—	—	
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OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)								
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EXAMINER: <i>J. Lee G.</i>				DATE CONSIDERED: <i>05/04/03</i>				
<small>*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.</small>								

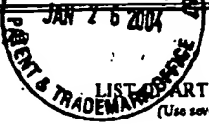
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Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. M212-1748		SERIAL NO. 09/879,231	
PARENT OR PREDECESSOR BY APPLICANT (Use several sheets if necessary)				APPLICANT: Gero J. Dordarian			
				PRIORITY FILING DATE June 11, 2001		GROUP 2818	
U.S. PATENT DOCUMENTS							
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
TL	AA	09/590,795		Agarwal et al. (as filed and amended 10/29/01 & 1/6/03)			06/00
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*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							

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Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. M272-1743		SERIAL NO. 09879231		
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT <u>Gero J. Dordick</u>				
				FILING DATE June 11, 2001		GROUP 2418		
U.S. PATENT DOCUMENTS								
*Exhibit or Initial		Document Number	Date	Name	Class	Subclass	Filing Date if Appropriate	
<u>RL</u>	AA	6,531,391	04/03	Each et al				
<u>RL</u>	AB	6,780,704	06/04	Rademaker				
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OTHER REFERENCES (including Author, Title, Date, Publication Page, Etc.)								
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EXAMINER <u>Thane</u>				DATE CONSIDERED <u>11/11/04</u>				
*EXAMINER: List all references considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.								



Form PTO-101

U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICE

LIST OF ART CITED BY APPLICANT
(Use several sheets if necessary)

ATTY. DOCKET NO.
M22-1748

SERIAL NO.
09/879,231

APPLICANT Gero J. Dardarian

FILING DATE
June 11, 2001

GROUP
2818

U.S. PATENT DOCUMENTS

Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
<i>TR</i>	AA	6,162,712	12/00	Baum	—	—	—
<i>TR</i>	AB	6,018,065	01/00	Baum	—	—	—
<i>TR</i>	AC	6,281,543	08/01	Al-Shareef et al	—	—	—
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FOREIGN PATENT DOCUMENTS

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OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)

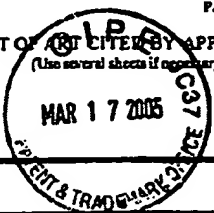
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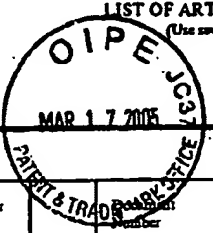
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DATE CONSIDERED *11/11/01*

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. M122-1748		SERIAL NO. 09/879,231		
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary) <div style="text-align: center;">  </div>				APPLICANT Garo J. Derderian				
				FILING DATE June 11, 2001		GROUP 2818		
U.S. PATENT DOCUMENTS								
Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
TU	AA	6,482,740	11/02	Soiminen et al	—	—	—	
	AB	5,908,947	06/99	Vaartstra	—	—	—	
	AC	6,403,156	06/02	Jang	—	—	—	
	AD	6,746,930	06/04	Yang	—	—	—	
	AE	2002/0142488	10/02	Hong, Suk-Kyoung	—	—	—	
✓	AF	2005/0018381	07/03	McClure	—	—	—	
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FOREIGN PATENT DOCUMENTS								
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OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)								
TU	AP		Suntola, "Surface Chemistry of Materials Deposition at Atomic Layer Level," Applied Surface Science, vol. 100/101, March 1996, pp. 391-398.					
TU	AQ		T. Suntola, Atomic Layer Epitaxy, Handbook of Crystal Growth, Vol. 3, 1994, pp. 603-663.					
TU	AR		Leskela and Ritala, ALD Precursor Chemistry: Evolution and Future Challenges, J. Phys. IV France 9 (1999), pages 837-852.					
TU	AS		Ritala et al, "Perfectly Conformal TiN and Al ₂ O ₃ Films Deposited by Atomic Layer Deposition," Chemical Vapor Deposition, v. 5, No. 1, 1999, pp. 7-9.					
EXAMINER <i>Thur</i>				DATE CONSIDERED 04/02/05				
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.								

Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. M122-1748		SERIAL NO. 09/879,231	
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT Garo J. Derderian			
							
				FILING DATE June 11, 2001		GROUP 2818	
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TR	AA 09/653,156		Agarwal (as amended 8/12/02, 2/18/03, 10/13/03, 3/30/04, 12/27/04)	—	—	08/2000	
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<small>*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with new communication to applicant.</small>							